A DIALLEL ANALYSIS OF CELLULAR MEMBRANE THERMOSTABILITY IN COMMON BEAN (<u>PHASEOLUS</u> <u>VULGARIS</u> L.)

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A Diallel Analysis of Cellular Membrane Thermostability in Common Bean (<u>Phaseolus</u> <u>vulgaris</u> L.)¹

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Abstract. To estimate the genetic component of cellular membrane thermostability in <u>Phaseolus vulgaris</u>, parental and F_1 plants from a 6-parent half diallel cross were tested by electrical conductivity and the results were analyzed by Hayman's method. Membrane thermostability was found to be a quantitative trait, with environmental and dominance effects accounting for most of the phenotypic expression. Narrow sense heritability was low (5.4%).

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It is well known that high temperature is one of the major factors limiting yield of common bean. In order to breed for heat tolerance, one needs information about the inheritance of the character and a suitable method of screening for it.

Screening methods and inheritance of heat tolerance in common beans have been studied by several researchers. Benepal and Rangappa (3) screened 5380 accessions for their ability to set pods in the field. Wien and Munger (31) also tested lines for heat tolerance in the field. Weaver et al. (29) suggested a possible screening procedure testing pollen growth <u>in</u> <u>vitro</u> or <u>in vivo</u>. Ng and Bouwkamp (21) rated more than 600 accessions according to their response to high temperature in the greenhouse. Bouwkamp and Summers (4) reported on the inheritance of combined temperature and drought stress resistance based on the number of pods set per plant.

In addition to morphological characters, methods of measuring cell viability have been tested in the hope of finding a rapid laboratory screening procedure. The electrical conductivity method is the most important of these. It tests for cell membrane thermostability as measured by leachate conductivity and has recently been

used as an index of viability after heat treatment. Various plant species and parts have been examined by the conductivity test. Laminar pieces of tomato and epidermal strips from onion bulb were tested by Onwueme (22), holly root cells by Ingram (12), and pear suspension cells by Wu (32). A diversity of turf grasses has been tested by with this method (28,30); and Chen et al. (6) have examined tomato, soybean, and potato.

Comparison of the electrical conductivity test with other methods and with field performance suggests that the electrical conductivity method is a moderately reliable and convenient screening procedure for measuring heat tolerance. Marsh et al. (18) measured heat tolerance in common bean by the conductivity test, a hot water dip, percent pod set, and pollen stainability. They concluded that the conductivity method best combined reliability with early testing convenience. Marsh et al. (17,19) reported for the conductivity method that the killing times for the 5 genotypes used were in agreement with previous ratings from yield data. They also studied heat tolerance inheritance by conductivity tests for the parents, F1, backcross, and F₂ populations from 3 crosses of heat-

tolerant X heat-intolerant lines. Schaff (23) observed significant correlation of electrical conductivity with field performance under heat stress, developed a sigmoidal model to calculate killing temperature, and conducted a 6-parent weighted diallel analysis to determine the inheritance of heat tolerance. In soybean and sorghum, good correlation has been found between heat tolerance as measured by electrical conductivity and field performance measured by yield (20, 25).

The Hayman-Jinks diallel cross has been widely used for inheritance studies (5, 14), despite the fact that some reports have been openly critical of the diallel analysis as a method for studying the genetics of complex traits or as a tool in plant breeding (8). Johnson (14) pointed out two major advantages that the diallel cross provides: compared to other methods available, the diallel cross technique permits a more systematic approach to large scale studies of continuous variation and a better diciplined analysis of the resulting data; and the overall analysis provides reliable genetic information on dominance and recessiveness and on complementary non-allelic interaction.

The diallel analysis makes it possible to predict

the phenotypes of the completely dominant parents, which in turn suggests the possible limit of selection among genes showing dominance. Baker (2) emphasized the fact that similar information could be obtained from different methods of analyzing diallel crosses, such as those developed by Griffing (9) and Gardner and Eberhart (7). The assumptions required for the genetic interpretation in self-pollinating plants were evaluated by Sokol and Baker (24). Jones (15) modified the Hayman-Jinks method so that it can be conducted without reciprocal crosses (half-diallel analysis).

The objective of this experiment was to carry out a six parent half-diallel analysis to determine the inheritance of heat killing time in common bean.

Material and Methods

Three of the parents used in this study are cultivars previously reported to be heat tolerant (23, 31): PI 324607 (P_2), ND 364 (P_4), Wyoming 166 (P_5). The other three are heat intolerant (23): PI 271998 (P_1), Oregon 1604 (P_3), Valley (P_6). Valley, Wyoming 166, and ND 364 were obtained originally from M. LeBaron, University of Idaho, Kimberly; PI 271998 and PI 324607 from the USDA Plant Introduction Station, Pullman, WA; and Oregon 1604 from the Idaho Seed Bean Co., Twin Falls, ID. All cultivars have been maintained by single seed descent for at least four generations.

The half-diallel cross was made in winter 1984. The seeds of each parent were sown in 5.5 X 5.5 X 5.0 cm pots containing a potting mixture of vermiculite, peat, perlite, and soil; and the pots were put in a growth chamber set for 30 C and a 16-hr light period to ensure rapid and uniform germination. Ten days from seeding, the seedlings were transplanted into one-gallon pots containing the same soil mixture as in the seeding pots. The plants were maintained in a greenhouse set for 28/22 C day/night temperature and supplementally lighted to approximate a 12-hr photoperiod to ensure uniform timing of flower initiation. The crosses were made by hand

pollination as soon as the plants began flowering. Cultivars with dominant marker genes were used as male parents whenever possible.

In fall and winter of 1985, 4 runs of the conductivity test were carried out, each containing 1 plant for each of the 21 accessions (15 F_1 hybrids and 6 parents). In each run, 2 to 3 seeds of each genotype were sown, transplanted, and maintained in the greenhouse as previously described. One plant of each genotype was tested for membrane stability in a random sequence. The time schedule for each run is listed in Table 1.

The plants to be tested were acclimated at flowering stage for 24 hours in growth chambers set for a constant 37.5C and a 16-hr photoperiod at 900 μ E sec⁻¹ m⁻². Immediately after acclimation the young, fully expanded leaves were picked for testing by the procedure of Kinbacher (16) with the following modifications.

Leaf discs, one cm in diameter, were washed with deionized-distilled water, changed 3 times, and put into test tubes, 5 per tube, each containing 1 ml of water. The treatment tubes were kept in a water bath set at 47C for 30, 60, 90, 120, 150, and 180 minutes, for each of the accessions with 3 replications for each time.

Control discs were held at room temperature. After the tubes cooled, 20 ml of deionized-distilled water were added to each and they were incubated at 10 C for 24 hours. The first conductivity was determined at 25C after incubation. All of the tubes were put in boiling water for 15 minutes to kill the cells completely. After 24 hours at room temperature, the second conductivity reading was taken at 25C.

Relative leakage, or injury, was calculated using the equation:

Relative leakage = 1 - $[(1-(C_1/C_2))/(1-(C_{1c}/C_{2c}))]$, where C_1 = treatment first conductance, C_{1c} = control first conductance, C_2 = treatment second conductance, and C_{2c} = control second conductance.

The killing time (Time50) is defined as the time at which 50% cell were injured. Viability was estimated using the sigmoidal equation:

Viability = $1 / [1 + e^{-B(Time - Time 50)}] + \epsilon$

where B is a rate parameter and ϵ is the deviation from the regression line (27).

The error term for the diallel analysis was the MS ERROR, the mean square interaction of cross X run, which can be obtained by fitting the sigmoidal model to

various sets of data (Table 2).

The diallel weighting and analysis procedure followed that of Schaff (23) with modifications and is given in the appendix. The same notation was used as by Hayman (10). The caculations were conducted using the SAS computer language.

Results and Discussion

The Hayman-Jinks diallel model assumes: parental homozygosity, diploid segregation, no differences between reciprocal crosses, no multiple alleles, no epistasis, and no linkage between the genes studied.

The first three assumptions were confirmed to be valid by observation of parental and hybrid phenotypes. The remaining three were tested with the methods of Hayman (10) and Jinks (13), namely, uniformity of $W_r - V_r$. The t-test for heterogeneity of $W_r - V_r$ is not significant (t=0.046, P=0.97), and Figure 1 shows that the regression slope of W_r on V_r is not significantly different from unity (for b=1, P = 0.30). Consequently, there is insufficient evidence to say that Hayman's model is inappropriate for this experiment.

The mean killing time (Time50) and its coefficient of the standard error (K) for each genotype are presented in Table 3. Due to the large standard errors of Time50 and the small mean square residuals of the sigmoidal model, K values are relatively large. The relative position of the parents for heat tolerance is similar to Schaff's results (23).

Since only six parents were intercrossed in the

present study (less than ten parents), the genetic components estimated are appropriate only for this particular set of parents, rather than for the entire population (10,11).

The main components of genetic variance are listed in Table 4, and the estimates of heritability parameters are given in Table 5. Since $(H_1/D)^{1/2}$, which estimates the degree of dominance, is larger than 1, overdominance exists, as also indicated by the negative intercept in Figure 1. Also, the correlation coefficent between the parental order of dominance (W_r+V_r) and the weighted parental values is very close to 0 (r=0.00008, P=0.99), indicating that there are equal numbers of positive and negative genes showing dominance. Marsh et al. (19) also found that the F_1 mean killing time exceeded the midparent for all 3 crosses studied and interpreted the fact as gene interaction. Since their data also fit the additive-dominant model with small epistatic effects, this "gene interaction" means dominance.

For our results, the ratio of dominant to recessive genes equals 1.40, indicating that there are more dominant than recessive genes for heat tolerance. There is at least one gene group showing some degree of dominance, as indicated by the estimate, $h^2/H_2 = 0.52$.

The proportion of genes with positive and negative effect in the parents, $H_2/4H_1$, is 0.23, possibly indicating slightly unequal distribution of positive or negative genes among parents.

Significant differences were found among runs (Table 6), which suggests that unknown environmental factors affected plants by causing different responses to the heat stress among runs even for the same cross. Tal and Shannon (26), also using the leaf disc conductivity test for membrane heat stability, found that all Lycopersicon and Solanum species tested had more injury in the winter than in the summer. The results of our experiment support this because, as shown in Table 1, overall means of each run decreased as the treatment date shifted. So weather conditions, such as light intensity and daylength, may account for some of the variation among runs, among crosses, and among plants of the same cross. In order to obtain a more accurate estimate of the inheritance, the present conductivity procedure needs to be refined to minimize environmental error. Additional replication of genotypes tested, both within and between runs, would give more accurate estimation of killing times.

The estimate of narrow sense heritability is low (5.4%), which contrasts with the high heritability (59%) observed by Schaff (23). Several factors should be taken into consideration when comparing these two results. Firstly, some of the bean lines he used differed from those of this study. Secondly, his experiment was an unbalanced split plot design using killing temperature, not killing time. Thirdly, his original data were not homogeneous for W_r-V_r until one parent, Oregon 1604, was removed.

By comparing the estimate of broad sense heritability (34.6%) and that of narrow sense heritability, it is clear that the dominant effects accounted for most of the genetic variation.

The narrow and broad sense heritabilities of heat tolerance calculated by Marsh et al. (19) for their different parental crosses ranged from 2.9% to 24% and 0.0% to 21.6%, respectively. Our narrow sense heritability (5.4%) is within their range, and its low value is due to the large environmental and dominant effects and the small additive effects. Also, the estimate of the heritability in this experiment was based on individual plant responses, where large errors of estimation were common. We conclude that membrane thermostability in common bean is a quantitative trait and easily influenced by the environment. Dominant effects accounted for most of the genetic variation. Because of the low heritability of cellular membrane thermostability, should the conductivity method be employed in a breeding program, continuous evaluation and selection using large samples will be required in later generations. Even then, the time- and laborconsuming nature of this procedure makes it difficult to use. Unless the test can be improved in these respects, alternative testing procedures will have to be developed for an effective heat-tolerance breeding program.

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32. Wu, M. T. and Stephen J. W. 1983. Heat stress responses in cultured plant cells. Plant Physiol. 72: 817-820. Table 1. Time schedule and overall mean Time50 for each run.

Run	Planting	Testing	Mean
1	09/25/85	11/06/85	120.4
2	10/16/85	11/26/85	112.2
3	11/08/85	12/18/85	111.0
4	12/09/85	01/16/86	8 5. 3

Table 2. Error term calculation.

Source	<u>Sum square residual</u>	<u>d.f.</u> ^z
All plants	SSRes(ALL)	crtn-m
Run	SSRes(RUN)	r(ctn-m)
Cross	SSRes(CROSS)	c(rtn-m)
Each plant	SSRes(PLANT)	cr(tn-m)

z c = No. of genotypes, including parents; r = No. of runs; t = No. of time intervals tested/plant; n = No. of test tubes/time interval; and m = No. of parameters in the sigmoidal model.

SS(CROSSXRUN) = SS ERROR = SSRes(CROSS)+SSRes(RUN)-SSRes(ALL)-SSRes(PLANT)

d.f. ERROR = d.f. SSRes(CROSS) + d.f. SSRes(RUN)

-d.f.SSRes(ALL) - d.f.SSRes(PLANT)

MS ERROR = MS(CROSS X RUN) = SS ERROR / d.f_{ERROR}

Table 3. The killing time (Time50) and its coefficient of the standard deviation (K) for the parents and their F_1 hybrids.

	<u>P1</u> ^z	<u>P2</u>	<u>P3</u>	<u>P4</u>	<u>P 5</u>	<u>P6</u>
P 1	76.8 ^y 62.3 ^x					
P 2	100.8 64.2	84.5 49.5				
P3	111.3 55.4	114.1 93.9	108.3 49.5			
P ₄	113.1 57.4	128.8 54.7	81.3 48.4	97.7 48.4		
P 5	101.1 54.9	140.9 61.1	124.0 54.7	107.1 52.7	1 23.3 55.6	
P ₆	105.6 50.6	110.8 57.5	117.0 65.5	106.6 54.6	103.6 58.4	96.0 48.3

 ^z P₁ = PI 271998, P₂ = PI 324607, P₃ = Oregon 1604, P₄ = ND 364, P₅ = Wyoming 166, and P₆ = Valley.
 ^y Time50, mean value for 4 runs; LSD_{0.05} = 28.65.
 ^x K, mean value for 4 runs. Table 4. Genetic variance components for killing time.

<u>Genetic</u> <u>component</u> ^z	Estimate and standard error ^y
D	74.9 <u>+</u> 125.5
H ₁	46 8. 7 <u>+</u> 3 1 8. 5 [*]
H ₂	43 5. 2 <u>+</u> 2 8 4. 5 *
F	61.9 <u>+</u> 306.5
h ²	226.0 <u>+</u> 191.5
Е	227.6 <u>+</u> 47.4 ^{**}
z D = additive effects	of genes;
H ₁ = dominance effect	s of genes;
H ₂ =dominance indicat negative effects	ed by asymmetry of positive and of genes;
F = covariance of dor	minance and additive effects;
h ² =square of the dom heterozygous phas	ninance effects over all loci in se in all crosses; and
E = environmental er	ror.
^y *, ** significant at	20%, 1% level, respectively.

Table 5. Hayman's heritability parameters.

Inheritance parameters ^z	<u>Estimate</u>
$(H_1/D)^{1/2}$	2.50
H ₂ /4H ₁	0.23
κ _D /κ _R	1.40
h ² /H ₂	0.52
Narrow sense heritability	0.054
Broad sense heritability	0.346

 $z (H_1/D)^{1/2}$ = average degree of dominance;

H₂/4H₁ = average frequency of positive vs negative alleles;

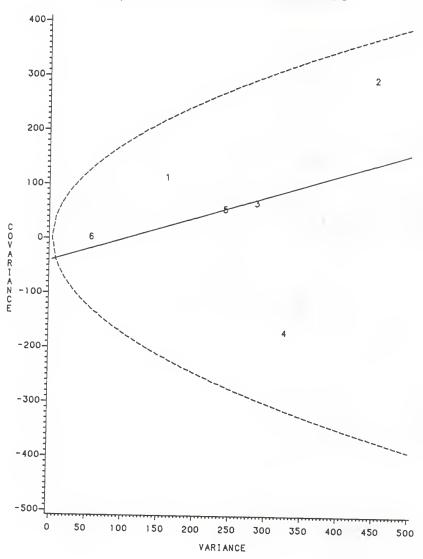
 $K_D/K_R = ((4DH_1)^{1/2} + F)/((4DH_1)^{1/2} - F)$ the ratio of dominant to recessive alleles;

 h^2/H_2 = average number of genes showing dominanance; Narrow sense heritability = $(1/4)D/[(1/4)(D-F+H_1)+E]$; Broad sense heritability= $(1/4)(D-F+H_1)/[(1/4)(D-F+H_1)+E]$. Table 6. ANOVA table of mean killing times for the half diallel cross.

Source	<u>d.f.</u>	<u>Mean</u> square
Cross	20	953.76 ^{**} 4848.77 ^{**}
Run	3	4848.77**
Error	60	410.29
Total	83	

** significant at 1% level.

Figure 1. Graph of variance vs. covariance (V_r, W_r) of 6 bean cultivars for heat tolerance.



VR/WR DIALLEL 6 PARENTS



10 FIT THE SIGMCIOAL MODEL TO ALL PLANT, TO RUN, * ø TC CRCSS, AND TO EACH PLANT -DATA ALL: INPUT PLANT 1-2 TIME 5-7 A1 10-13 1 A2 15-18 1 A3 20-23 1 A4 25-28 1 A5 30-33 1 Ao 35-38 1 RUN 40 P1 45 P2 50; IF P1=3 CR P2=3 THEN DELETE: IF PI=1 AND P2=1 OR PI=1 AND P2=1 THEN CROSS="1X1"; IF P1=1 AND P2=2 OR P1=2 AND P2=1 THEN CRESS=*1X2*; IF PI=1 AND F2=3 OR PI=3 AND P2=1 THEN CRCSS=*1X3*; IF PI=1 AND P2=4 OR PI=4 AND P2=1 THEN CRCSS=*1X4*; IF PI=1 AND P2=5 OR PI=5 AND P2=1 THEN CRCSS=*1x5*; IF PI=1 AND P2=6 CR PI=6 AND P2=1 THEN CRCSS=*1x6*; IF P1=2 AND P2=3 CR P1=3 AND P2=2 THEN CRCSS=*2x3*: IF P1=2 AND P2=4 OR P1=4 AND P2=2 THEN CRCSS="2X4". IF P1=2 ANC P2=5 OR P1=5 AND P2=2 THEN CRCSS="2x5"; IF P1=2 AND P2=6 CR P1=6 AND P2=2 THEN CRESS="2x0"; IF P1=3 AND P2=3 OR P1=3 AND P2=3 THEN CRCSS=*3X3*; IF P1=2 AND P2=2 OR P1=2 AND P2=2 THEN CRESS="2x2"; IF P1=3 AND F2=4 OR P1=4 AND P2=3 THEN LRCSS=*3X4*; IF P1=3 AND P2=5 CR P1=5 AND P2=3 THEN CRCSS=*3x5*; IF PI=3 AND P2=6 OR P1=6 AND P2=3 THEN CRCSS=*3X0*; IF P1=4 AND P2=4 OR P1=4 AND P2=4 THEN CRCSS=*4X4*; IF P1=4 ANU P2=5 OR P1=5 AND P2=4 THEN CRCSS=*4x5*; IF P1=4 AND P2=6 OR P1=6 AND P2=4 THEN CRESS="4x6"; IF P1=5 AND P2=5 OR P1=5 AND P2=5 THEN CRCSS=*5X5*. IF P1=5 ANC P2=0 OR P1=6 AND P2=5 THEN CRCSS="5x0"; IF PI=6 AND P2=6 CR PI=6 AND P2=6 THEN CRCSS=*6x6*; REP=1: R=1-(A1/A4): OUTPUT: REP=2: R=1-(A2/A5); CUTPUT; REP=3; R=1-(A3/A6); CUTPUT; OROP A1-A6; CAROS: DATA CNE: SET ALL: PROC SCRI; BY PLANT; DATA THO; SET CNE; IF TIME > 0 THEN DELETE: PROC MEANS NEPRINT: BY PLANT: VAR R; OUTPUT OUT=NEW MEAN=RC: GATA THREE: SET NEW; PROC SCRT; BY PLANT; DATA COND: MERGE ONE THREE: BY PLANT: IF TIME = 0 THEN DELETE; READ=1-(R/RC); PROC NLIN; PARMS 8=.01 TC .3 8Y .1 U=50 TO 180 8Y 3U; L=EXP(-B*(TIME-U)); MODEL READ=1/(1+L); 0ER.U=-L+B/(1+L)++2; 0ER.2=(TIME-U)+L/(1+L)++2; CUTPUT OUT=MCCALL R=REACALL PARMS=BALL UALL ESS=SSRESALL;

PRUC SCRI DATA=COND; BY CROSS; PROC NLIN ; EY CROSS; PARMS 8=.01 TO .3 BY .1 U=50 TO 180 BY 30; L=EXP(-8*(TIME-0)); MODEL READ=1/(1+L); OER.8=(T1ME-6)+L/(1+L)++2; CUTPUT OUT=NEWC P=PREADC PARMS=BC UC ESS=SSRESC; PROC MEANS N NCPRINT; BY CROSS; VAR READ; OUTPUT OUT=NEWC N=NC; DATA NEWC;SET NEWC: BY CRCSS; IF FIRST.CRCSS; DATA CROSSI; MERGE NEWC NEWO; BY CROSS; OFC=NC-2; **UATA CROSS2;SET CRCSS1;** PROC SCRT; BY DESCENDING UC; PROC MEANS SUM; VAR SSRESC DEC; OUTPUT OUT=NEWC SUM=SSSRESC SDFC; PROC SCRI DATA=CDND; BY RUN; PROC NLIN; BY RUN; PARMS B=.D1 IC .3 BY .1 L=5D TO 18D BY 3D; L=EXP(-B+(TIME-U)); MODEL READ=1/(1+L); DER.E=(TIME-L)4L/(1+L)442; DER.U=-L+8/(1+L)++2; OUTPUT CUT=NEWR P=PREADR PARMS= BR UR ESS=SSRESR; PROC MEANS N ACPRINT; BY RUN; VAR READ; CUTPUT OUT=NEWS N=NR; CATA NEWRISET NEWRIBY RUN; IF FIRST-RUN; DATA RUNI;MERGE NEWR NEWS;BY RUN; DFR=NR-2: DATA RUN2;SET RUN1; PROC SCRT; BY DESCENDING UR; PROC MEANS SUMEVAR SSRESH OFR: PRCC PRINT; PROC NLIN; EY PLANT; PRAMS 8=.01 TC .1 8Y .02 U= 30 TO 150 BY 30; L=EXP(-8*(11#E-6); MODEL READ=1/(1+L); GER.B=(T1ME-U)+L/[1+L)++2; DER.U=-L*8/(1+L)**2; CUTPUT OUT=NEWA P=PREAD PARMS=BP UP ESS=SSRESP; PROC PRINT:

APPENDIX-B

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              PARENT 1 = PI 271998
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                    2 = PI 324607
                                                                        •
                    3 = OREGON 1604
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                    4 = ND 364
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                    5 = WYGMING 166
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÷.
                    6 = VALLEY
                                                                        ø
DATA TEST;
INPUT RUN 5 TIME50 10-13 1 STOER 15-20 4 MSRES 25-28 5 P1 35 P2 40;
SIEU=STDER/SCRI(MSRES);
STEU=STEU+STEU;
SIGCP=.066075:
CARDS:
PROC SCRT: BY PL P2:
PROC MEANS MEAN; BY PL P2; VAR TIME50 STEU;
CUTPUT OUT=DATA MEAN=TIME50 K;
DATA CATA: SET DATA; K=SCRT(K);
PROC MEANS MEAN DATA=TEST NOPRINT;8Y P1; VAR TIME50;
CUTPUT GUT=NUME MEAN=TIME50;
PROC MEANS N DATA=NUMB NOPRINT; VAR TIME5C;
CUTPUT CUT=NUMBER N=NP;
DATA NUMBER; SET NUMBER; KEEP NP;
DATA CO:INPUT L S GG:CARDS;
CGRR STE_CORR PR_CCR=D
DATA A: INPUT A $ ad; CARDS;
VARIANCE COVAR N+V H-V Y YR STNCRD_Y PARAEOLA RANK_CRD
DATA 8; INPUT 8 $ 22; CARDS;
O F H1 H2 SHGR E
DATA E: INPUT E S aa; CARDS;
D_OF_OCH POS:NEG DCH:REC GENES
DATA G; INPUT G & aa: CARDS;
VOLD VILI WOLGI VOLI MLI_MLO MLI_MLG2 O F H1 H2 HSWR ERROR
DATA X: LNPUT X 5 .... CARDS;
INTERCET SLOPE(B) B_ERROR
DATA GO: INPUT RUN & ad;CARDS;
W-V_HOM PR_W-V_HOM 8=0 PR_8=0 8=1 PR_8=1
DATA ERROR; SET TEST;
IF _N_ =1;
KEEP SIGCP;
PROC MATRIX;
FETCH P DATA=NUMBER: ****CATA SET WITH NUMBER OF PARENTS UNLY;
FETCH E CATA=ERRCR: ****CATA SET WITH ERRCR TERM UNLY:
U=J(P,P,D); ****GBSERVATION VALUES;
K=J(P,P,C); **** VALUES FOR WEIGHTING;
UR=J(P,I.D);
AR=J(P+1+0);
SR=J(P,1,0);
VR=J(P,1,D); .... VARIANCE IN AN ARRAY;
R=J(P,1.0); ....CVARIANCE IN AN ARRAY:
OBUILD DIALLEL DATA ARRAY:
IK=NROW(C);
OETERMINE NUMEER OF MEANS IN DIALLEL:
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00 I=1 TO IK;
P1=Q(I,1);
                    0000P1, PARENT 1;
P2=Q(1,2);
                    ♦♦♦♦₽2, PARENT 2;
                    ..... OBSERVARTION VALUES MATRIX;
U(P1,P2)=Q(1,3);
U(P2,P1)=Q(I,3);
                    K(P1+P2)=G(I+4);
                    0000K, WEIGHT MATRIX;
K(P2,P1)=Q(I,4);
                    OOOOK, WEIGHT MATRIX;
ENO:
PRENT Q U K:
GIALLEL ARRAY IS MATRIX U;
UII=VECDIAG(U); +++++ PARENT OBSERVATION VALUES:
K00=SSC(K)#/(P#P):
                            **** AVERAGE VALUE OF WEIGHT;
E=E#K00:
                            **** ERROR CORRECTED FUR MEAN VALUES;
KII=VECOLAG(K);
                            0000 PARENT WEIGHT VALUES:
UP=SUM(UII#/(KII#K1I))#/SSQ(1#/KI1);
PRINT UII KOO E KII UP;
OG I=1 TO P;
UR(I=1)=SUM(U[=1)#/(K[=])#K[=1)))#/SUM((12/(K(=I)=K[=I))));
AR(I+1)=SUM(U(+I)#/(K(+1)#K(+I)));
SR(1,1)=SUM(1#/(K(,1)*K(,1)));
VR(I,1)=(14/(P-1))#(SSQ((U(+I)#/K(+I)))-(UR(I+1)#UR(I+1))#SUM((1#/(K(+I)#K(+I))
1)) #KOC:
WR(1,1)=(1a/(P-1))a(SUM(((UII-UP)a/K1I)a(U(,I)-UR(I,1))a/K(,i))aKOG;
END:
PRINT UR AR SR VR WR;
VCLO=(1#/(P-1))*(SUM((UII#/KII)#(UII#/KII))-(UP#UP#SUM(1#/(KII#KII)))=KOO;
VILI=SUM(VR(+1))#/P;
WGL01=SUM(WR(+1))#/P;
VCLI=(1#/(P-1))#(SSC(AR)-(SUM(AR#SR)++2#/SSU(SR)))#KCO#KOG#/(P#P);
MLI_MLO=((SUP(\a/(K#K))#/SUM(I#/(K#K)))-(SUM(U11#/(K1I#K11))#/SUM(I#/(K11#K11)))
1:
ML1_ML02=MLI_MLC++2;
N=P ;
PRINT VOLO VILI WELCI VOLI MLI_MLO2 MLI_MLO N P;
OCM=VCLO-E;
F=2+V0L0-4++CLC1-((2+(N-2))+E)#/N;
H1=VCLC-4*WOLC1+4*V1L1-(((3*N)-2)*E)#/N;
H2=4*V1L1-4*VCL1-2*E;
HSQR=4+ML1_MLC2-(4+(N-1)+E)#/N++2;
DEG_DEM=SGRT(H1#/DEM);
POS_NEG=H2#/(4+H1);
DOM_REC=(SCRT(4+COM+H1)+F)#/(SURT(4+OCM+H1)-F);
GENES=HSCR#/H2:
COOM=[N**5+N**4]#/[N**5];
CF=((4*(N**5))+(20*(N**4))-(16*(N**3))+(16*(N**2)))#/(N**5);
CH1=(N**5+(41*(N**4))-(12*(N**3))+(4*(N**2)))#/(N**5);
CH2=[36*[N**4])#/[N**5];
CHSQR=[[16+[N++4]]+[16+[N++2]]-[32+N]+16]#/[N++5];
CE=(N++4)#/(N++5);
W_V=WR-VR;
W_PLUS_V=WR+VR;
STANCARO ERRCRS OF ;
S2=[[SSG[W_V]-[[SUM[W_V]]++2]#/N]#/[[N-1]#2]];
SCOM=SCRT((CECF+S2));
SF=SGRIL(CF+S2));
SH1=SCRT((CH1+S2));
SH2=SQRT((CH2+S2));
SHSQR=SQRT((CHSQR+S2));
SE=SGRT[[CE+S2]];
ERROR_OF= SDCMIISFIISHIIISH2IISHSGKIISE;
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34 * I TEST STAST FOR O F H1 H2 HS4 ERROR: DCMIT=COM#/SCCM: IF OCMIT > O THEN OT=-1+DCMIT; IF OCMIT < O THEN OT=DOMIT; FTT=F#/SF; IF FTT > C THEN FT=-1#FTT; IF FTT < 0 THEN FT=FTT; HITT=H1#/SHI; IF HITT > O THEN HIT=-1+HITT; IF HITT < C THEN HIT=HITT; H2TT=H2#/SH2; IF H2TT > 0 THEN H2T=-1+H2TT; IF H2TT < 0 THEN H2T=H2TT; HSQRTT=HSQR#/SHSQR; IF HSORTT > C THEN HSCRT=-I+HSCRTT: IF HSORTT < 0 THEN HSORT=HSORTT; EIT=E#/SE: IF ETT > 0 THEN ET=-1*ETT; 1F ETT < 0 THEN ET=ETT; POT=PRCBT(CT,N-1); PO=2*PCT; PFT=PROBT(FT,N-1); PF=2*PFT; PHIT=PROBT(H1T, N-I); PHI=2*PHIT: PH2T=PRO8T(H2T,N-1); PH2=20PH2T; PHSQRT=PROBT(HSCRT,N-1); PHSQR=2*PHSCRT: PET=PRCAT(ET,N-1); PE=2*PET; PROB_T=POIJPF1JPH1JJPH2JJFHSQRJJPE; NGTE DIALLEL CRCSS DATA; PARENT=UII'; SIDCCV=(SSG(WR)-((SUM(WR)**2)#/N))#/(N-1); STOPAR=SCRT(VCLC4K00); STOVAR=(SSC(VR)-((SUM(VR)+2)#/N))#/(N-1); PM=SUM(PARENT)#/N; WM=SUM(WR)#/N; VM=SUM(VR)#/N; YR=Ull'#/KIL'; SIO_Y=(PARENT-LP)#/(STOPAR#KII*); RO=RANK(H_PLUS_V); PARABOLA=SCRT(VR#VOLO); VR1=VR*;WRI=WR*;W_PLUSV=W_PLUS_V*;W_V1=W_V*;PAKABGL1=PARABCLA*; RC1=R0*; STATS=VR1//WR1//W_PLUSV//W_VI//PARENT//YR//STO_Y//PARABCL1//HU1; FETCH C DATA=A TYPE=CHAR; NOTE ARRAY STATISTICS; PRINT STATS ROWNAME=C; PLOT=STATS'; OUTPUT PLOT CUT=PLT1 IRENAME=(COL1=VARIANCE COL2=CCVAR COL3=w_PLUS_V COL4=W_V CCL5=Y COL6=YR CCL7=STNDRO_Y CCL8=PARAEOLA COL9=RANK_ORO ROW=PLT)); CUTPUT STATS CUT=PLT; MEANS=CEG_OOMIIPCS_NEGIIOCM_RECIIGENES; NGTE HAYMANS ANALYSIS QUANTIES; QUANTITY=VOLOIIVILIIIWOLCIIIVOLIIIMLI_MLOIIMLI_MLU2IIOOMIIFIIHIIIH2IIHSGRIIE; CUTPUT QUANTITY CUT=VCLG (RENAME=(CGL1=VOLU CCL2=V1L1 COL3=bOLGI COL4=VCL1 CCL5=MLI_MLO CCL6=MLI_MLC2 COL7=0 COL8=F COL9=H1 COL10=H2 COL11=HSQR COL12=ERRUR)); FETCH Y DATA=G TYPE=CHAR:

PRINT CUANTITY COLNAME=Y; FETCH X7 DATA=8 TYPE=CHAR; NOTE STANDARD ERRORS; PRINT ERROR_OF COLNAME=X7; NGTE T PROE=C;PRINT PROB_T CCLNAME=X7; FETCH Z DATA=E TYPE=CHAR; NOTE MEAN EFFECTS OVER ALL PARENTS; PRINT MEANS COLNAME=Z; MWV=SUM(W_PLUSV)#/N; C1=SUM((W_PLUSV-MWV)#(PARENT-UP)#/KII*); C2=SSQ(W_PLUSV)-((SUM(W_PLUSV)+2)#/N); C3=VOLO#K00#(P-1): CCRR=C1#/SCRT(C2*C3); STEC=SGRT((1-CCRR++2)4/(N-2)); CCRT=CCRR#/STEC; IF CCRT > 0 THEN CT=-1*CGRT; IF CCRT < 0 THEN CT=CORT; PROBCA=PRCET(CT+N-2); PROBC=2*PRCBCA; CCRR1=CCRR11STEC11PROBC; FETCH CO DATA=CO TYPE=CHAR; NOTE CORRELATION OF Y AND W+V; PRINT CORRI COLNAME=CC; VV_VH=(STOVAR-STCCCV)++2; VVXVH=(STOVAR*STCCOV); PCOV=VR2#R; CVRWR2=((SUM(PCCV)-((SUM(VR)¢SUM(WR))#/N))#/(N-1))¢¢2; T2=((N-2) + VV_Vh)4/((VVXVh-CVRHR2)+4); B1=SUM(VR#WR)-((SUM(VR)*SUM(WR))#/N); 82=SSQ[VR-VM]; 8=81#/82: SE=SGRT(((STECCV*(N-1))-(8*B1))#/((N-2)*82)); D1F_0=8#/S8; DIF_1=(1-8)#/SE; IF T2 > 0 THEN T2A=-1+T2; IF T2 < 0 THEN T2A=T2; IF DIF_0 > 0 THEN DIFC=-1+DIF_0; IF DIF_I > C THEN DIFI=-1+DIF_I; IF OIF_O < O THEN OIFC=OIF_O; IF OIF_1 < O THEN OIFI=OIF_1;</pre> PROBIZA=PRCBT(IZA+N-1); PROBIZ=2*PROETZA: PROBAC=PROET(CIFC+N-2); PROBO=2*PROBAC; PROBAL=PROBT(CIFL,N-2); PROBI=2*PRCBAI; INTERCEP=WM-E*VM; NOTE GRAPH STATISTICS: GRAPH=INTERCEPIIBIISB; FETCH XI DATA=X TYPE=CHAR; OUTPUT GRAPH CUT=LINEI (RENAME=(COLI=INTERCPT COL2=SLCPE CCL3=STERR_B)); PRINT GRAPH CCLNAME=X1: TTEST=T211PRCET211DIF_011PR0E011DIF_111PRCE1; FETCH X2 DATA=GC TYPE=CHAR; NCTE T TEST STATISTICS FOR: PRINT TIEST CCLNAME=X2; NCTE NARROW SENSE HERITABILITY ESTIMATES; HRITELTY=(0.25*0CM)#/((0.25*(00M+H1-F))+E); PRINT HRITELTY: PROC CORR DATA=PLT1; VAR YR W_PLUS_V: PROC REG DATA=PLT1; MCDEL COVAR=VARIANCE; DATA PLTL; SET PLTL;

IF PLT='ROW1' THEN DD; C1=CDVAR;PLANT='PI 271998 * END; IF PLT='RGW2' THEN DD; C2=COVAR;PLANI='PI 324607 ';ENU; IF PLT='RGW2' THEN DU; L2=LUVAR;FLANT='GREGON 16D4';END; IF PLT='RCW3' THEN DD; C3=CQVAR;PLANT='ND 364 ';END; 'S GLT='BOLL' THEN DD: C4=CQVAR;PLANT='ND 364 ';END; IF PLT='ROW4' THEN DO; C4=COVAR; PLANT='ND 364 IF PLT='ROWS' THEN DO; CS=COVAR; PLANT='WYCMING 166'; END; IF PLT='ROW6' THEN DO; C6=CCVAR;PLANT='VALLEY * : END : OATA PARAB: SET VOLO: X1=0.5+(0.5*SCRT(1-((4*(WOLOI-VILI))/VOLO))); x2=0.5-(0.5*SCRT(1-((4*(WOLOI-VILI))/VCLOI)); VD1=VCL0+X1++2; WC1=VOLO+X1: VR1=VGL0+X2++2; WR1=VOLO#X2; INTER=WOLDI-VILI: WPV=WOLOI+VILI; PROC PRINT; DATA PARABI;SET PARAB; X=VD1;Y1=WD1;VAR=0;CCV=INTER;OUTPUT; X=VR1;Y1=WR1;VAR=VR1;COV=WR1;DUTPUT; X=VILI;Y1=#GLCI;VAR=.;CGV=.; OUTPUI; KEEP X Y1 VAR COV; DATA RUNI; SET VCLD; DO VARIANCE=D TC 500 BY 5; PAR82=-1+(SCRT(VARIANCE+VCLD)); OUTPUT;ENO; KEEP PARB2 VARIANCE; PROC SCRT; BY CESCENDING VARIANCE; DATA L2;SET LINEL; DD VARIANCE=0.CO TO 500 BY 5; L2=INTERCPT + (SLOPE+VARIANCE); OUTPUT;END; DATA RUN;SET VCLO; DO VARIANCE=D.CO TO 50D BY 5; PAR82=SQRT(VARIANCE*VCLO); DUTPUT;END; KEEP PARBZ VARIANCE: PROC SORT: BY VARIANCE: DATA RUNZ;SET RUNI RUN; GATA PLCT;SET PLT1 RUN2; LABEL CI=CCVARIANCE; PROC REG CUTEST=EST DATA=PLT1; MCDEL YR=W_PLUS_V: PROC MEANS MEAN DATA=PLTI;VAR YR; GUTPUT OUT=MEANY MEAN=YR: DATA EST; SET EST; B=W_PLUS_V; TEST=1:KEEP TEST 8: DATA PARI;SET PARAB; KEEP WPV: DATA LINE; MERGE EST MEANY PARI; PROC SCRI; BY TEST; DATA WR;SET PLT1;TEST=1; YR1=YR; KEEP W_PLUS_V TEST YRL: DATA WRI: SET FARAB: W_PLUS_V=WD1+VC1;TEST=1;CUTPUT; W_PLUS_V=WR1+VR1;TEST=1;CUTPUT; KEEP TEST #_PLUS_V: DATA WR2;SET WR WR1; PROC SGRT; BY TEST; DATA GC: MERGE HR2 LINE ;BY TEST:

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EST=YR+(2*(W_PLUS_V-WPV));
PROC PRINT;
PROC PRINT; VAR YRI EST YR E W_PLUS_V WPV;
Data gplgt; set plct parael 12;
KEEP VARIANCE PAREZ X YI VAR COV CI CZ C3 C+ C5 Co PLANT L2;
PROC GPLOT:
TITLEI VR/WR DIALLEL 6 PARENTS:
SYMBOLI C=BLACK V=1 F=SIMPLEX;
SYMBCL2 C=BLACK V=2 F=SIMPLEX;
SYMBCL3 C=BLACK V=3 F=SIMPLEX;
SYMBGL4 C=ELACK V=4 P=SIMPLEX;
SYMBOLS C=BLACK V=5 F=SIMPLEX;
SYMBOL6 C=BLACK V=6 F=SIMPLEX;
SYMBOLB C=BLACK V=M H=2 F=SPECIAL L=1 I=JOIN;
SYMBGL9 C=BLACK L=I I=JOIN;
SYMBGLIO C=BLACK L=1 I=SPLINE;
SYMBGLII C=BLACK L=3 I=JGIN;
PLOT CI®VARIANCE=1 PARB2®VARIANCE=10 C6®VARIANCE=5
C20VARIANCE=2 C30VARIANCE=3 C40VARIANCE=4 C50VARIANCE=5 L20VARIANCE=9/0 .
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		000000000000000000000000000000000000000	******	*****		*****
L	T	845 63084	1830	2	2	
L	2	1028 65752	1079	3	2	
1	3	1213 37337	0652	3	3	
2	1	1864 114026		3	2	
2	2	1235 58557	1450	4	4	
3	3	1100 43536	0987	Ó	2	
3		943 54162	1226	L	1	
3	2	1349 51319 1361 54394	0995	5	2	
4	I I	1361 54394 1204 59871	0800	3	1	
4	2	847 60902	C861	6	4	
4	3	1262 50405	1091	2	1	
6	ĩ	873 69718	C901 1685	5	5	
6	ž	839 77033	1551	5	4	
0	3	1057 62555	1266	1 4	L	
7	ī	1351 43001	0764	3	4 1	
7	2	1145 50825	1021	5	3	
7	3	1251 6125C	1418	5	4	
В	L	1282 57053	1091	ŝ	3	
8	Z	1042 72143	1370	5	6	
8	3	1202 60832	1195	2	1	
9	L	1338 65940	0564	5	0	
9	2	1159 30205	6269	0	4	
9	3	1179 27855	0328	0	4	
10	1	1016 65841	1636	a	0	
10	2	1018 61908	1254	3	3	
10	3	1300 48544	0648	5	3	
11	1	1223 59766	1698	4	2	
11	2	851 56808	1135	5	1	
11	3	948 44423	C855	0	1	
12	1	930 25178	0319	6	1	
12	2	1547 52851	C675	5	5	
12	3	918 36653	C612	4	3	
13	2	1236 35018	0471	5	1	
13	3	831 47529 894 36708	C693	3	1	
14	ĩ	767 36962	0662	4	1	
14	2	1015 60145	C670 0822	4	3	
14	3	1167 54144	1193	5	2	
15	1	1807 107745	1374	5	6	
15	2	958 40807	0494	2	2 2	
15	3	1099 38644	0478	3	2	
16	L	1521 45733	0421	4	1	
16	2	994 69241	1340	4	1	
16	3	1083 42863	0946	6	6	
17	1	1367 85098	2150	5	3	
17	2	884 27732	0347	4	3	
17	3	950 35595	0598	ź	2	
81	L	1249 76041	1506	2	1	
18	2	1227 52269	C873	6	3	
18	3	1167 53654	0946	5	ī	
19	1	867 27896	0522	4	4	•
19	2	1590 89660	1457	4	2	

19	3	1272	34306	0560	4	2
20	1	1364	49092	C515	6	2
2 C	2	1409	39389	0422	6	1
20	3	1341	60538	1066	ó	3
21	1	958	63123	1391	5	5
21	2	1388	44630	0595	5	4
21	3	1212	31507	0448	5	2
1	4	791	67836	1286	5	1
2	-4	817	32954	0680	3	3
3	4	598	55568	1082	5	6
4	4	1115	47725	6871	4	1
5	4	769	63919	3137	6	6
6	4	661	60516	1373	4	3
7	4	698	45314	1029	6	4
8	4	733	74729	0906	2	1
9	- 4	939	37583	0625	6	1
10	4	826	166782	5146	6	3
11	- 4	1163	71097	1980	5	5
12	4	172	28658	0365	5	4
13	4	954	44030	0805	6	2
14	4	628	28770	0344	2	2
15	4	1065	62766	1753	4	2
16	- 4	704	52774	1033	1	1
17	- 4	1147	66900	1852	5	3
18	4	750	39684	0644	4	4
19	- 4	909	51495	0919	3	1
20	- 4	573	65231	· 1051	3	2
21	4	1268	35342	0761	5	2

A DIALLEL ANALYSIS OF CELLULAR MEMBRANE THERMOSTABILITY IN COMMON BEAN (<u>PHASEOLUS</u> <u>VULGARIS</u> L.)

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Abstract

To estimate the genetic component of cellular membrane thermostability in <u>Phaseolus</u> <u>vulgaris</u>, parental and F_1 plants from a 6-parent half diallel were tested by electric conductivity and the results were analyzed by Hayman's method. Membrane thermostability was found to be a quantitative trait, with environmental and dominant effects accounting for most of the phenotypic expression. Narrow sense heritability was relatively low (5.4%)